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Alberta, Edmonton, Canada, Surface and Interface Analysis, July 2012; <http://onlinelibrary.wiley.com/doi/10.1002/sia.5090/citedby>

- **Investigation of imaging ToF-SIMS as a means to study coatings on wood**, Mojgan Nejad, Paul Cooper, Rana Sodhi, Surface and Interface Analysis, Volume 43, Issue 1-2, pages 595-599, January-February 2011; <http://onlinelibrary.wiley.com/doi/10.1002/sia.3619/full>
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